

TDSEMIC

拓電半導體

自主封測 品質把控 售後保障

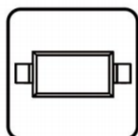
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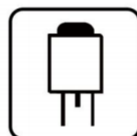
電源管理



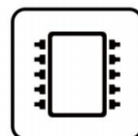
顯示驅動



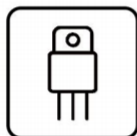
二三極管



LDO穩壓器



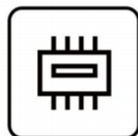
觸摸芯片



MOS管



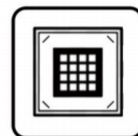
運算放大器



存儲芯片



MCU



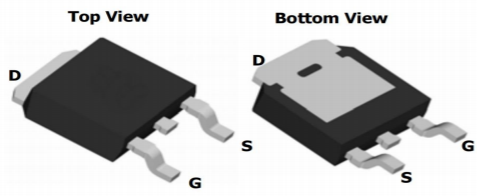
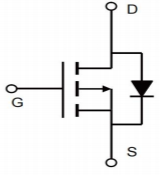
串口通信

TD40P04

產品規格說明書

P-Channel MOSFET TD40P04

Description

Features <ul style="list-style-type: none"> ● $V_{DS} = -40V$, $I_D = -40A$ $R_{DS(ON)} < 18m\Omega$ @ $V_{GS} = -10V$ $R_{DS(ON)} < 28m\Omega$ @ $V_{GS} = -4.5V$ ● Advanced Trench Technology ● Excellent $R_{DS(ON)}$ and Low Gate Charge ● Lead free product is acquired 	Application <ul style="list-style-type: none"> ● PWM Applications ● Load Switch ● Power Management <p>100% UIS 100% ΔV_{ds}</p>
 <p>TO-252</p>	 <p>Schematic Diagram</p>

Package Marking and Ordering Information

Device Marking	Device	OUTLINE	Device Package	Reel Size	Reel (PCS)	Per Carton (PCS)
TD40P04	TD40P04	TAPING	TO-252	13inch	2500	25000

Absolute Maximum Ratings ($T_C = 25^\circ C$ unless otherwise specified)

Symbol	Parameter		Max.	Units
V_{DSS}	Drain-Source Voltage		-40	V
V_{GSS}	Gate-Source Voltage		± 20	V
I_D	Continuous Drain Current	$T_C = 25^\circ C$	-40	A
		$T_C = 100^\circ C$	-26	A
I_{DM}	Pulsed Drain Current ^{note1}		-160	A
E_{AS}	Single Pulsed Avalanche Energy ^{note2}		144	mJ
P_D	Power Dissipation	$T_C = 25^\circ C$	41.6	W
$R_{\theta JC}$	Thermal Resistance, Junction to Case		3.6	$^\circ C/W$
T_J, T_{STG}	Operating and Storage Temperature Range		-55 to +175	$^\circ C$

Electrical Characteristics (T_J=25°C unless otherwise specified)

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
Off Characteristic						
V _{(BR)DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D = -250μA	-40	-	-	V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = -40V, V _{GS} =0V	-	-	-1	μA
I _{GSS}	Gate to Body Leakage Current	V _{DS} =0V, V _{GS} = ±20V	-	-	±100	nA
On Characteristics						
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D = -250μA	-1.0	-1.7	-2.5	V
R _{DS(on)}	Static Drain-Source on-Resistance note3	V _{GS} = -10V, I _D = -20A	-	15	18	mΩ
		V _{GS} = -4.5V, I _D = -10A	-	22	28	
Dynamic Characteristics						
C _{iss}	Input Capacitance	V _{DS} = -20V, V _{GS} =0V, f=1.0MHz	-	3800	-	pF
C _{oss}	Output Capacitance		-	329	-	pF
C _{rss}	Reverse Transfer Capacitance		-	289	-	pF
Q _g	Total Gate Charge	V _{DS} = -20V, I _D = -20A, V _{GS} = -10V	-	68	-	nC
Q _{gs}	Gate-Source Charge		-	10	-	nC
Q _{gd}	Gate-Drain(“Miller”) Charge		-	14	-	nC
Switching Characteristics						
t _{d(on)}	Turn-on Delay Time	V _{DD} = -20V, I _D = -20A, V _{GS} = -10V, R _{GEN} =2.4Ω	-	10	-	ns
t _r	Turn-on Rise Time		-	82	-	ns
t _{d(off)}	Turn-off Delay Time		-	93	-	ns
t _f	Turn-off Fall Time		-	74	-	ns
Drain-Source Diode Characteristics and Maximum Ratings						
I _S	Maximum Continuous Drain to Source Diode Forward Current		-	-	-40	A
I _{SM}	Maximum Pulsed Drain to Source Diode Forward Current		-	-	-160	A
V _{SD}	Drain to Source Diode Forward Voltage	V _{GS} =0V, I _S = -30A	-	-0.8	-1.2	V
t _{rr}	Reverse Recovery Time	V _{GS} =0V, I _S = -30A, di/dt=100A/μs	-	20	-	ns
Q _{rr}	Reverse Recovery Charge		-	13	-	nC

Notes: 1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature
2. EAS condition: T_J= 25°C, V_{DD}= -20V, V_G= -10V, L= 0.5mH, R_G= 25Ω, I_{AS}= -24A
3. Pulse Test: Pulse Width≤300μs, Duty Cycle≤2%

Typical Performance Characteristics

Figure 1: Output Characteristics

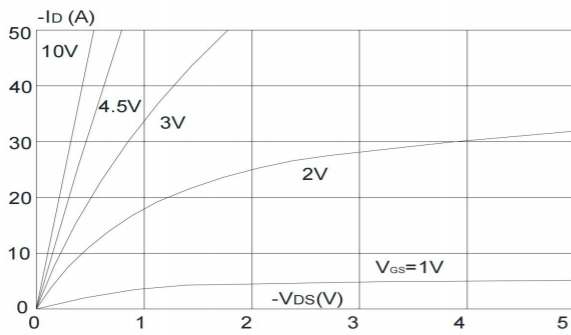


Figure 2: Typical Transfer Characteristics

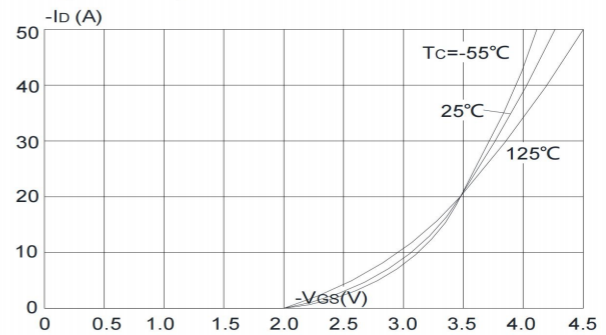


Figure 3: On-resistance vs. Drain Current

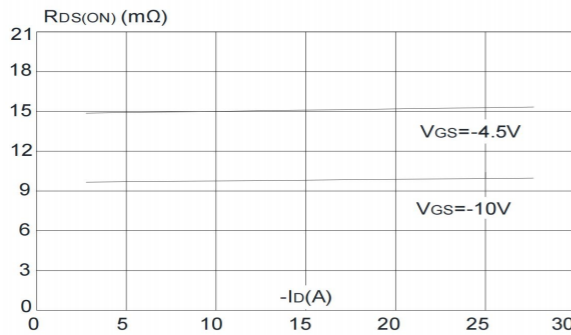


Figure 4: Body Diode Characteristics

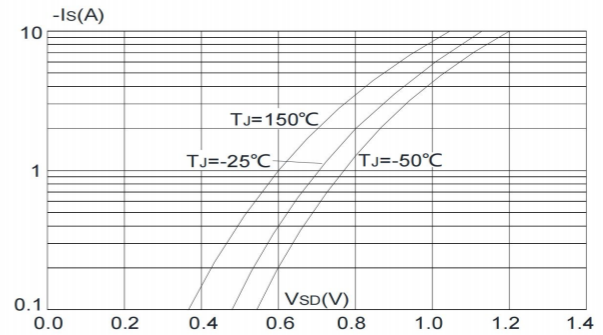


Figure 5: Gate Charge Characteristics

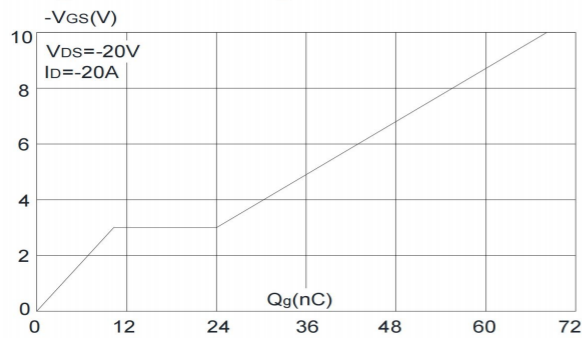


Figure 6: Capacitance Characteristics

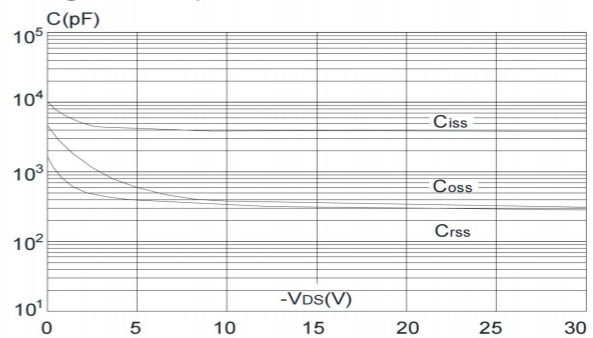


Figure 7: Normalized Breakdown Voltage vs. Junction Temperature

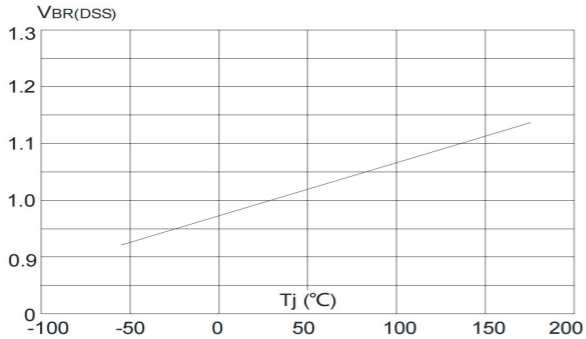


Figure 8: Normalized on Resistance vs. Junction Temperature

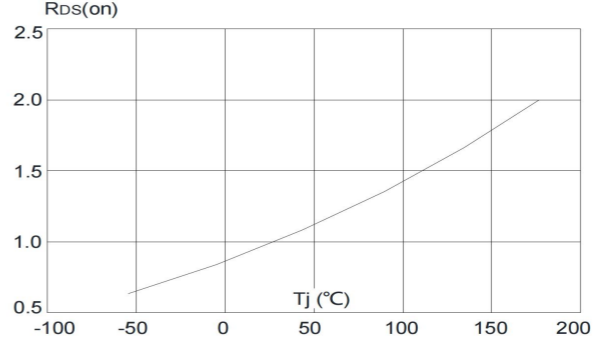


Figure 9: Maximum Safe Operating Area

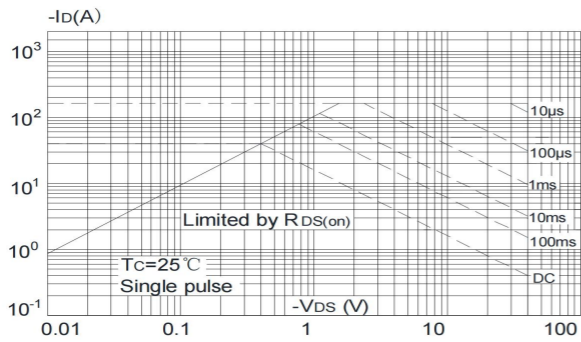


Figure 10: Maximum Continuous Drain Current vs. Case Temperature

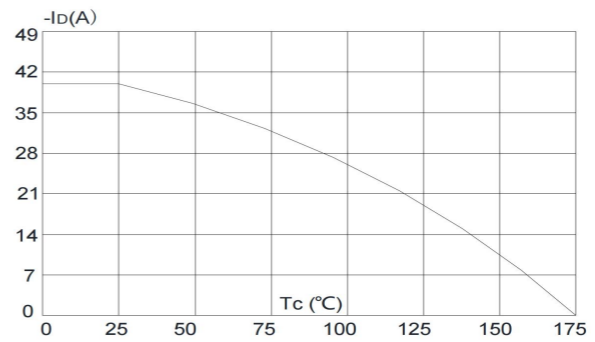
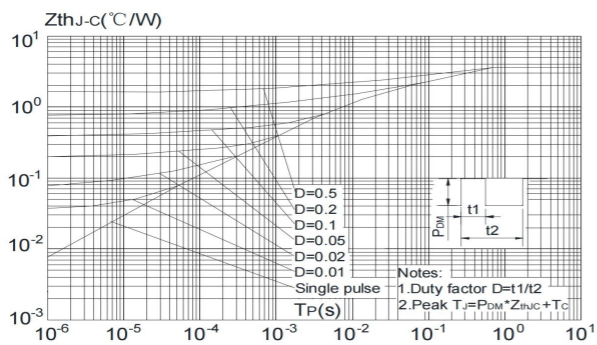
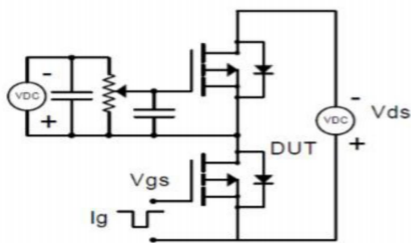
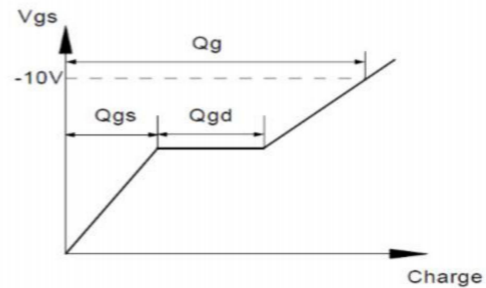


Figure.11: Maximum Effective Transient Thermal Impedance, Junction-to-Case

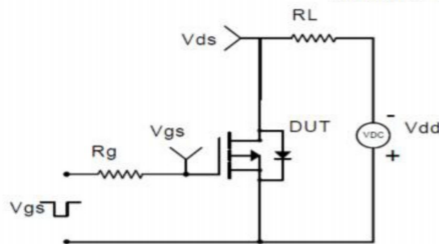
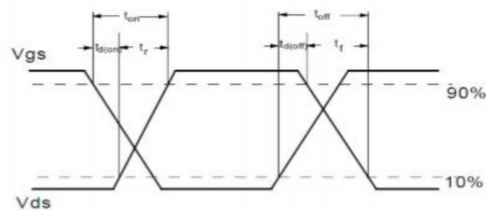


Test Circuit

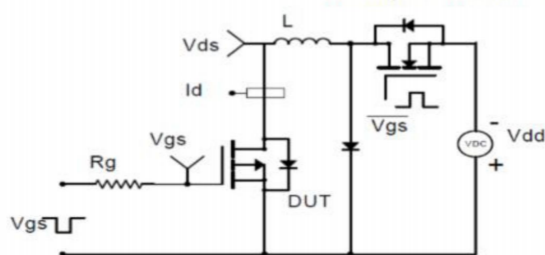
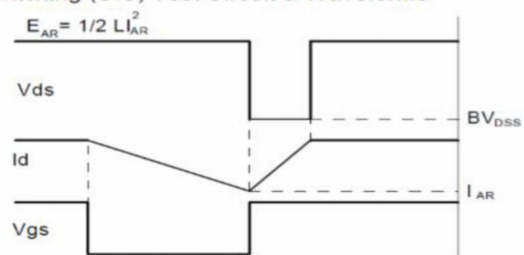
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

